

Degate

The stakes and challenges of silicon reverse engineering
<https://www.degate.org>

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Bière Sécu Rennes,

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Who am I?



Dorian Bachelot¹

- Currently a **Lead Product & Software Architect in Cybersecurity/AI** at NEVERHACK².
- Previously a master student doing **research on hardware reverse-engineering** at ESIEA³'s CNS laboratory.
- **Main maintainer of Degate** (since 2018).

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²<https://neverhack.com>

³<https://esiea.fr>



1 Chips Reverse Engineering

- Introduction

2 Degate

3 References

4 Bonus



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1 Chips Reverse Engineering

- Introduction

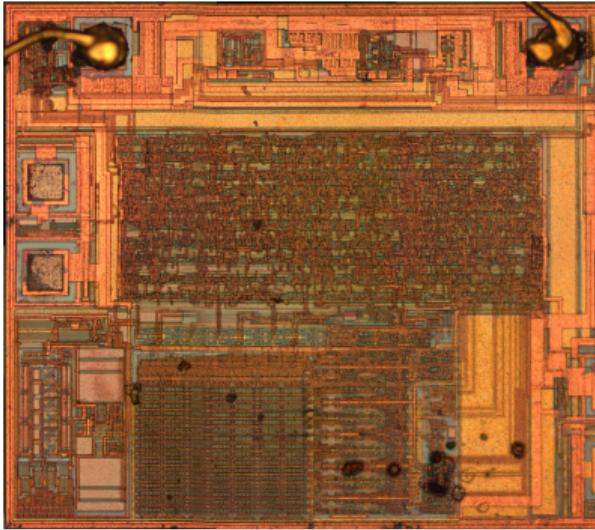
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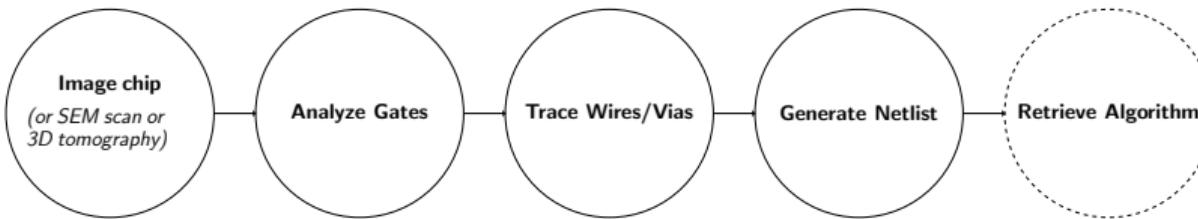
What is Silicon Chips RE?



Same idea than with software RE (from binary, to assembly and to code), chips RE go from silicon, to images, to transistors, to gates, to netlist and to algorithm.

With proper preparation and knowledge, we can go into silicon, analyze transistors, retrieve gates/wires/vias and reconstruct implemented algorithms. This can be used to analyze old hardware, build software emulators, search for vulnerabilities and backdoors, break/test a protection, secret extraction or check intellectual property.

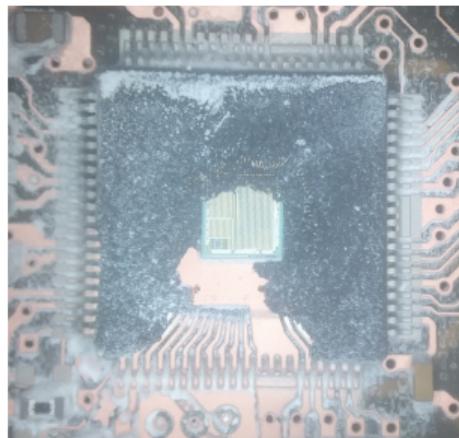
Used in IC industry for fault/failure detection & analysis, but not at the same scale.



How to Access Silicon?

Can be very costly (plasma & laser) and destructive... But also accessible with simpler methods (like chemical/mechanical). More on [4].

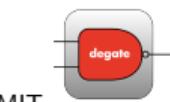
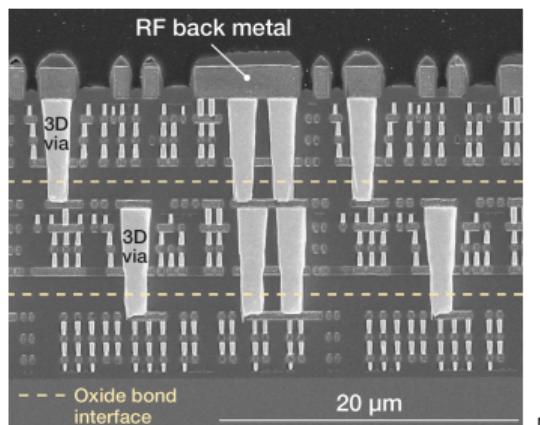
- ① **Decapsulation** (heat, acid, mechanical, plasma, laser...)
- ② **Delayering** (chemical, abrasive, laser, plasma...)
- ③ **Cleaning** (ultrasound, acid...)



[1]



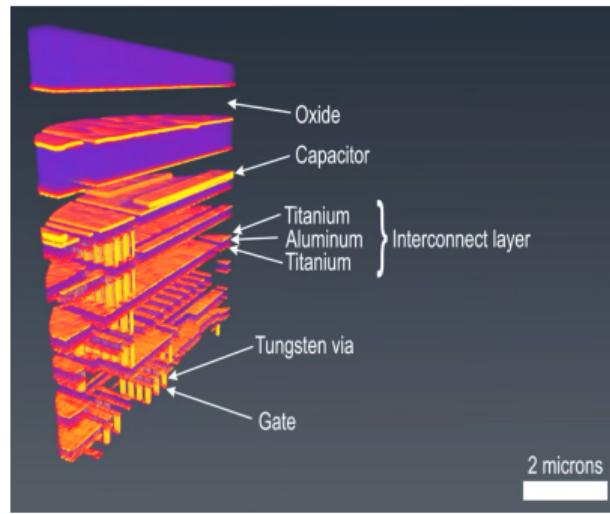
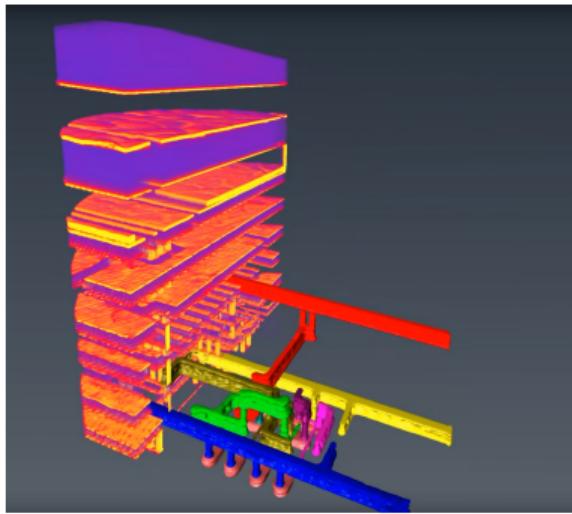
[2]



How to Retrieve Images?

Using each layer (invasive) or directly using the chip (non-invasive):

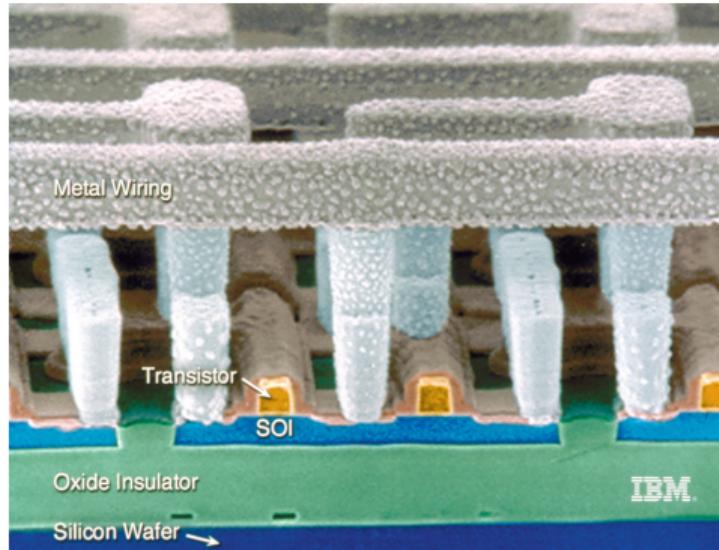
- Take very-high resolution images from **optical microscope** (basic, confocal) ;
- Scan from an **electron microscope** (SEM, TEM...) ;
- Generate a 3D model using **electron tomography** ;



How to Perform the Analysis?

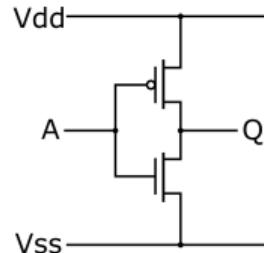
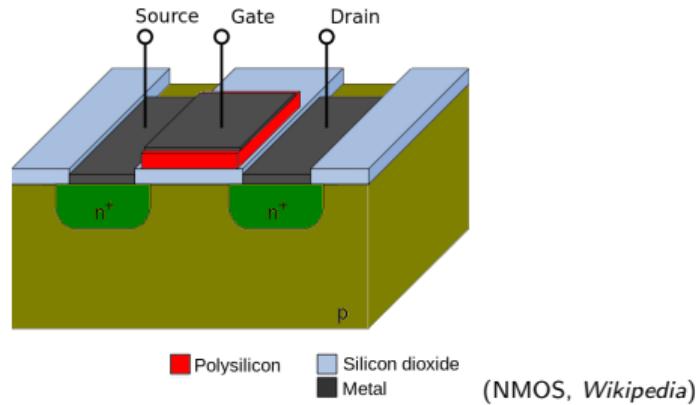
Overview:

- ① Choose a **zone of interest**,
- ② Identify each **gate type**, annotate, and place in a "**gate library**",
- ③ Find other **gates instance** from gate library,
- ④ Link gates by tracing **wires and vias**,
- ⑤ Export to **netlist** (e.g. by translating each gate to VHDL/Verilog code).

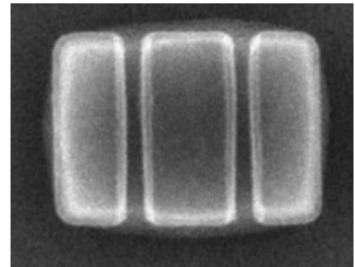


How to identify a transistor?

- ① Search, at transistor layer, for **doped zones**.
- ② Spot the **zebras**.
- ③ Use logic to identify the **type of each transistor** (e.g. PMOS are bigger to compensate with lower hole mobility).
- ④ Search for **wires** (to identify inputs and outputs).



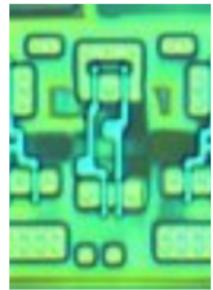
(Inverter, Wikipedia)



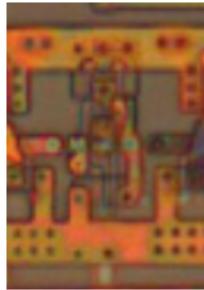
(PMOS [10])



How to Identify a Gate?



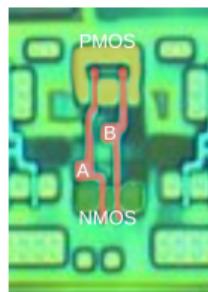
Transistor layer



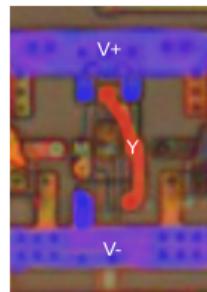
Logic layer



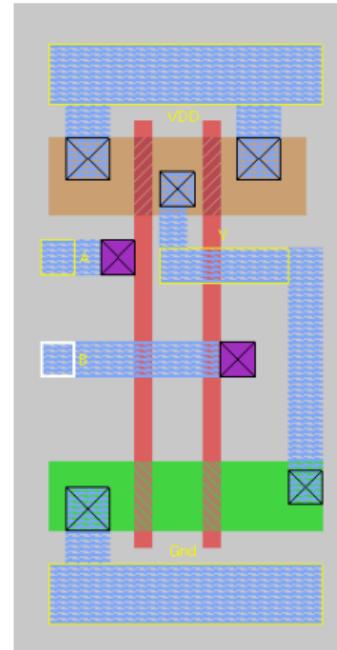
Metal layer



P & N zones and 2 inputs



V+ & V-, and output



[7] ⇒

NAND gate!

A	B	Y
0	0	1
1	0	1
0	1	1
1	1	0



How to Retrieve the Netlist from Analyzed Gates?

```

module jsrflipflop(q,qbar,clk,rst,sr);
    output reg q;
    output qbar;
    input clk, rst;
    input [1:0] sr;

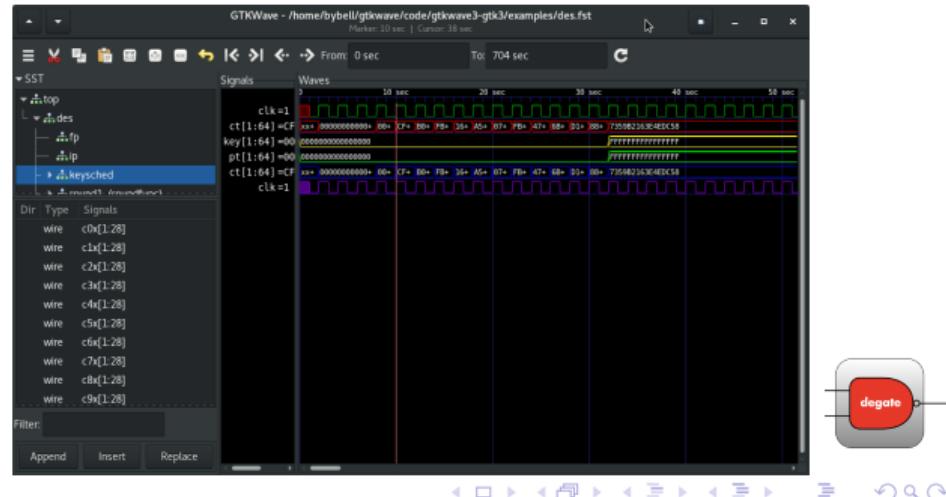
    assign qbar = ~q;

    always @(posedge clk)
    begin
        if (rst)
            q <= 0;
        else
            case(sr)
                2'b00: q <= q;
                2'b01: q <= 0;
                2'b10: q <= 1;
                2'b11: q <= 1'bx;
            endcase
    end
endmodule

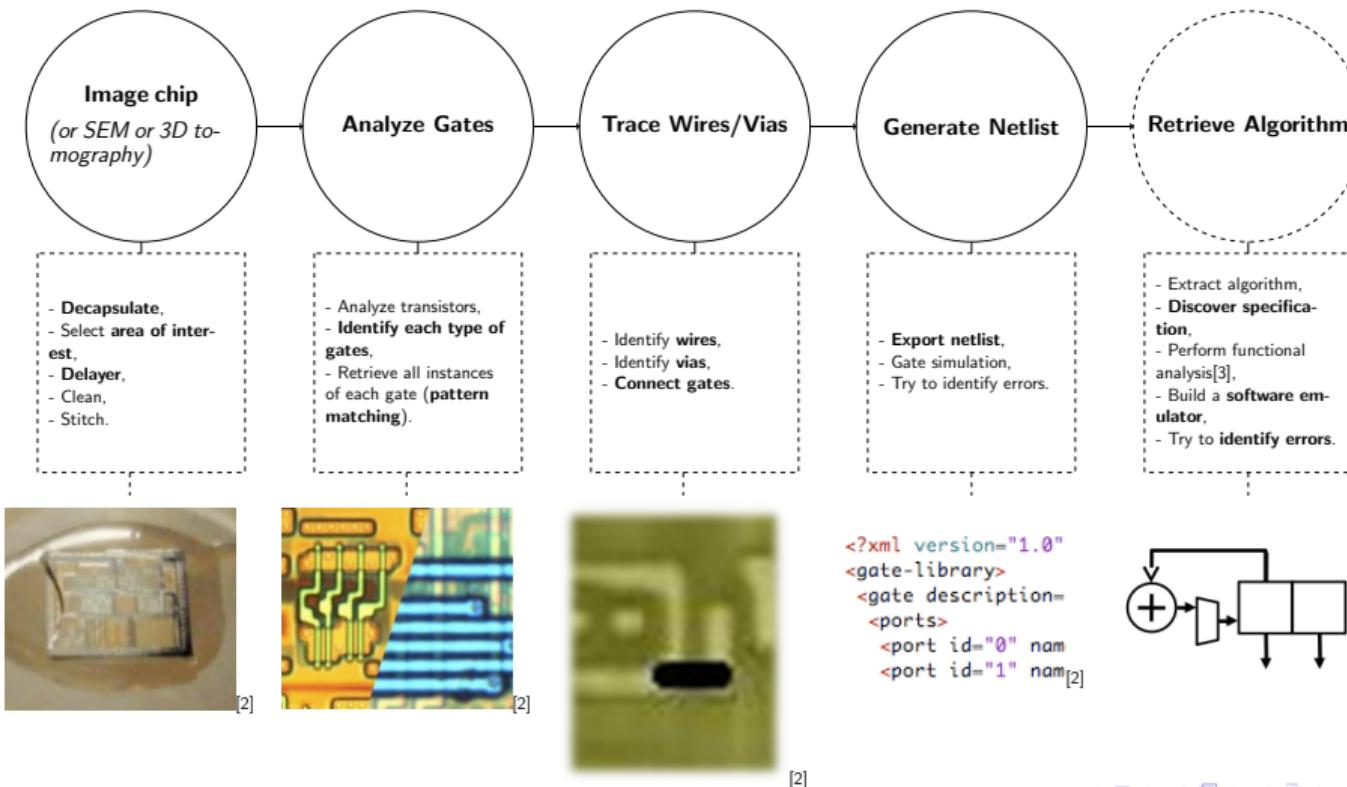
```

- Each gate can be described with **hardware description language (HDL)**, like **Verilog** or **VHDL**.
- Wires & vias can also be described.
- That's all we need to **obtain the netlist**!

We can, from HDL, **simulate the extracted netlist** and find **incoherence** (*example with gtkwave below*):



To Summarize



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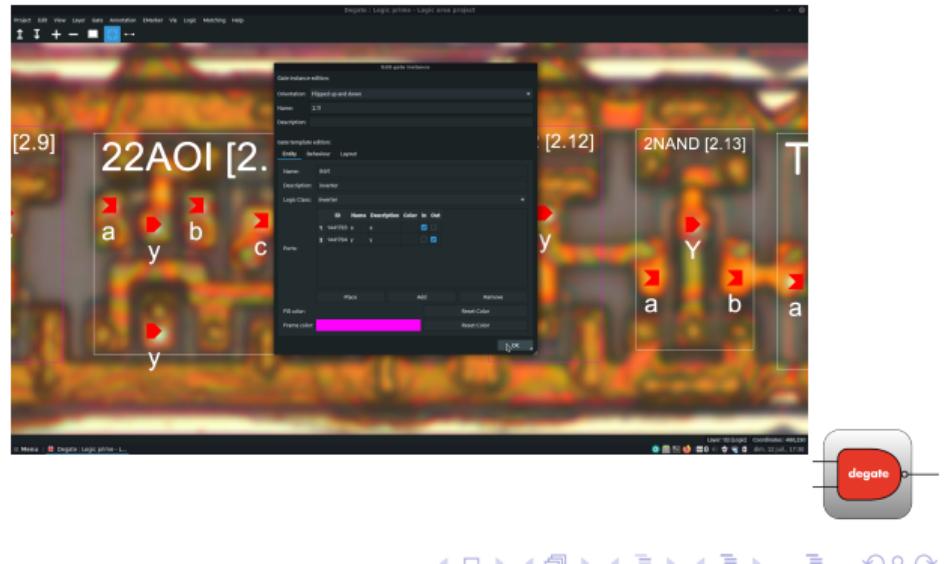
4 Bonus



Introduction

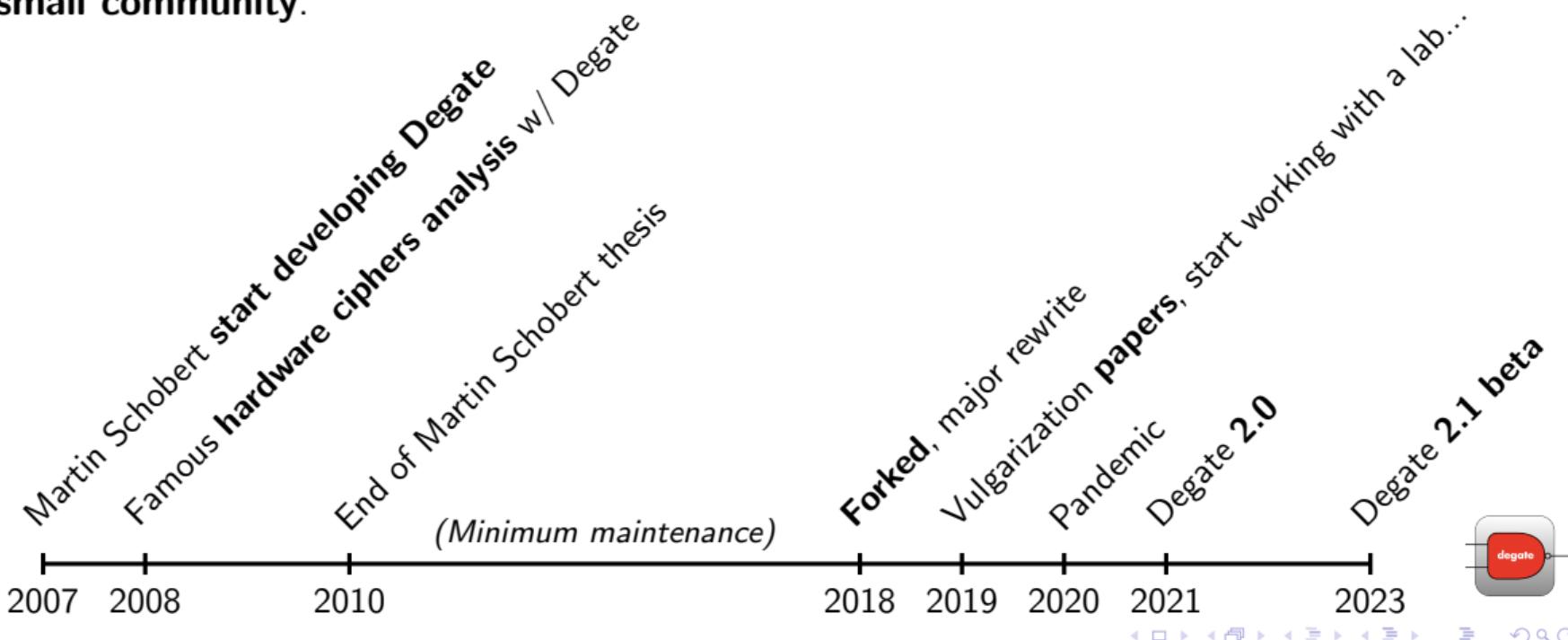
Degate is a multi-platform software for semi-automatic **Very-Large-Scale Integration (VLSI) chips reverse engineering** of digital logic in chips.

- ~70k LoC
- Supports Mac, Linux & Windows,
- Qt based,
- Multi-language support,
- Gate definition,
- Gate template, via & wire matching,
- Rule checks,
- ...



History

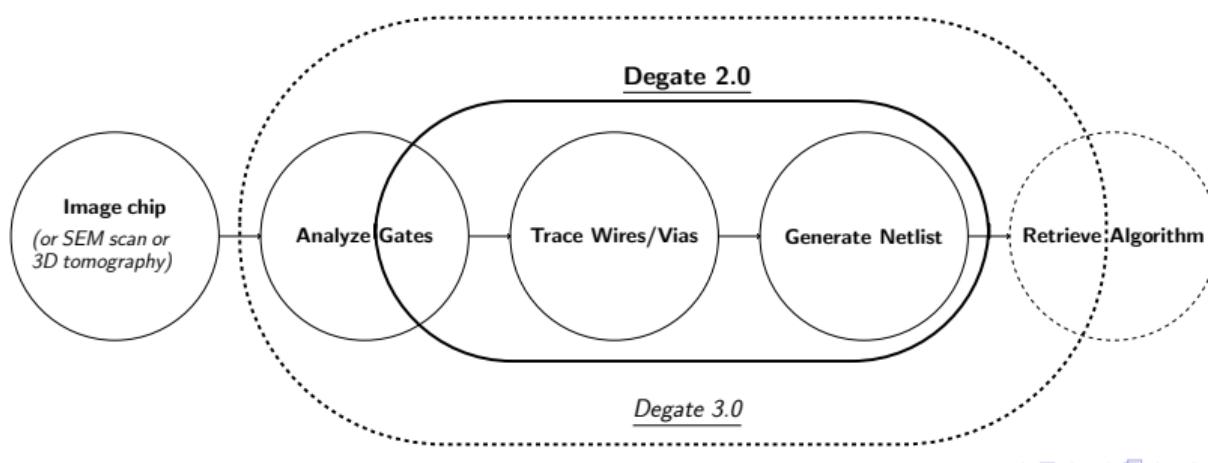
A long story, with **technical debt** and **major IC evolution** (in transistor count), along with a **small community**.



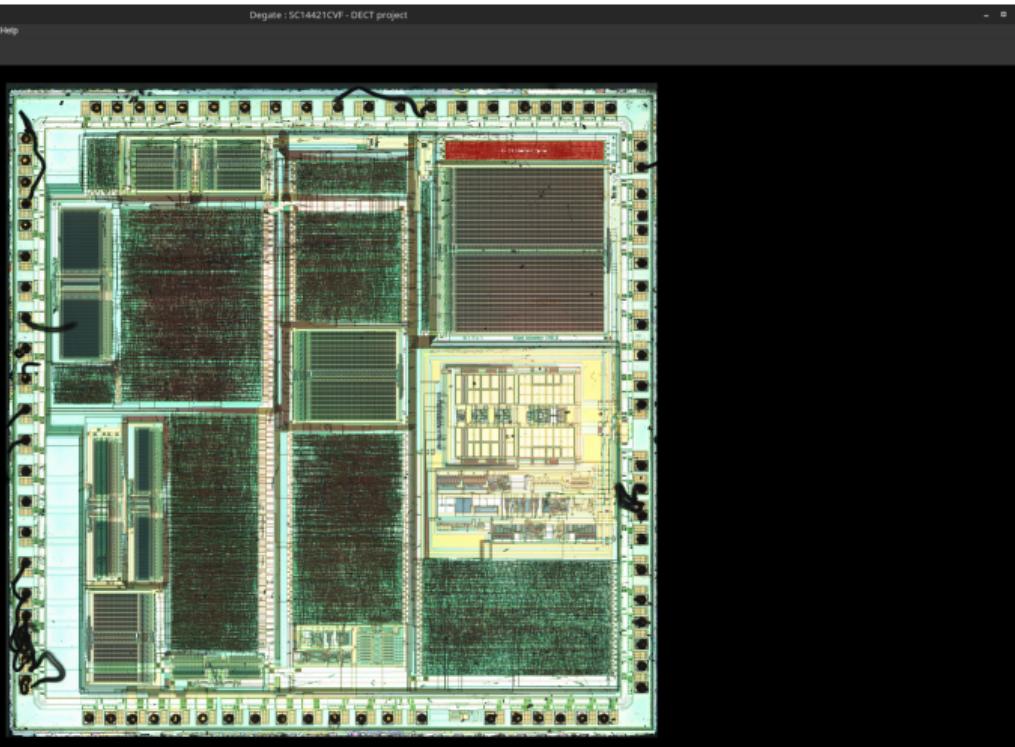
Usage

Degate help to reverse **VLSI chips** by creating an analyzed **gate library**, doing **template matching** to find gates instances from this library, **matching wires & vias**, **exporting netlist** and **navigating really huge images**.

Focus on **modern ICs** with **standard cells**, and supports **any 2D capture/imaging method** (SEM, optical...).



Small Demonstration

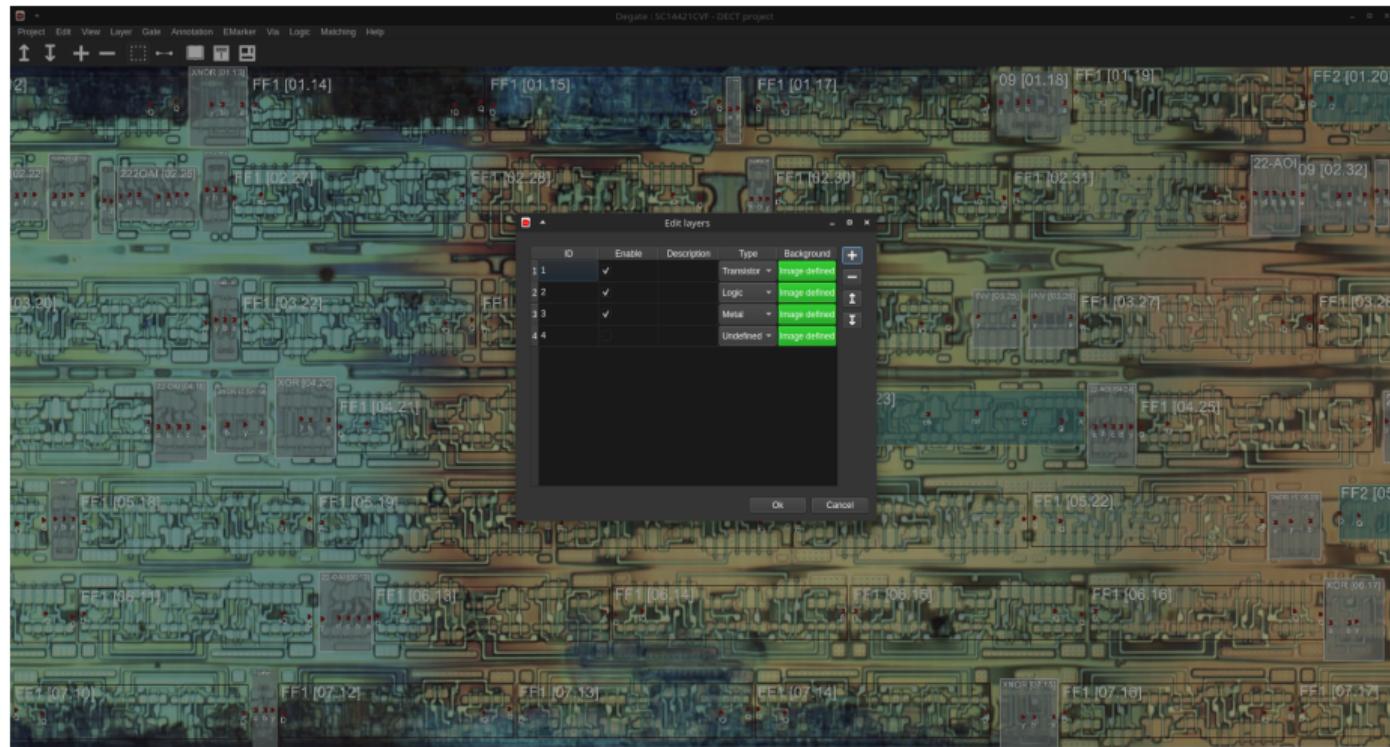


Overview of the chip, for zone of interest selection.

A sub-project can then be created on the zone of interest, and specific layers can be added (independent from the rest).



Small Demonstration

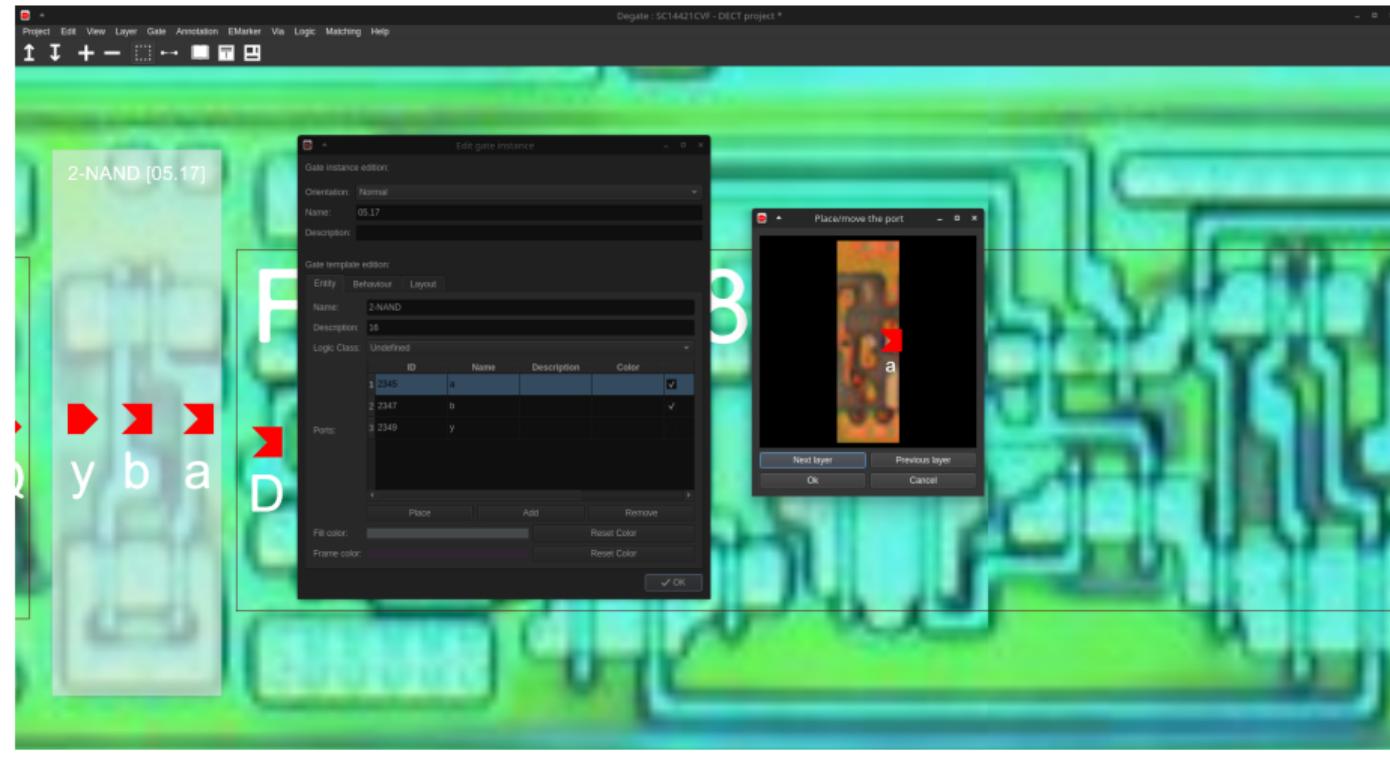


Each sub-project can contains multiple layers (pre-aligned images).

Two project mode: 1. For smaller images, will convert each images in Degate's format (for fast access) and 2. New (WIP, beta) mode for huge images (load only partial tiles in RAM, and doesn't change/import initial file).



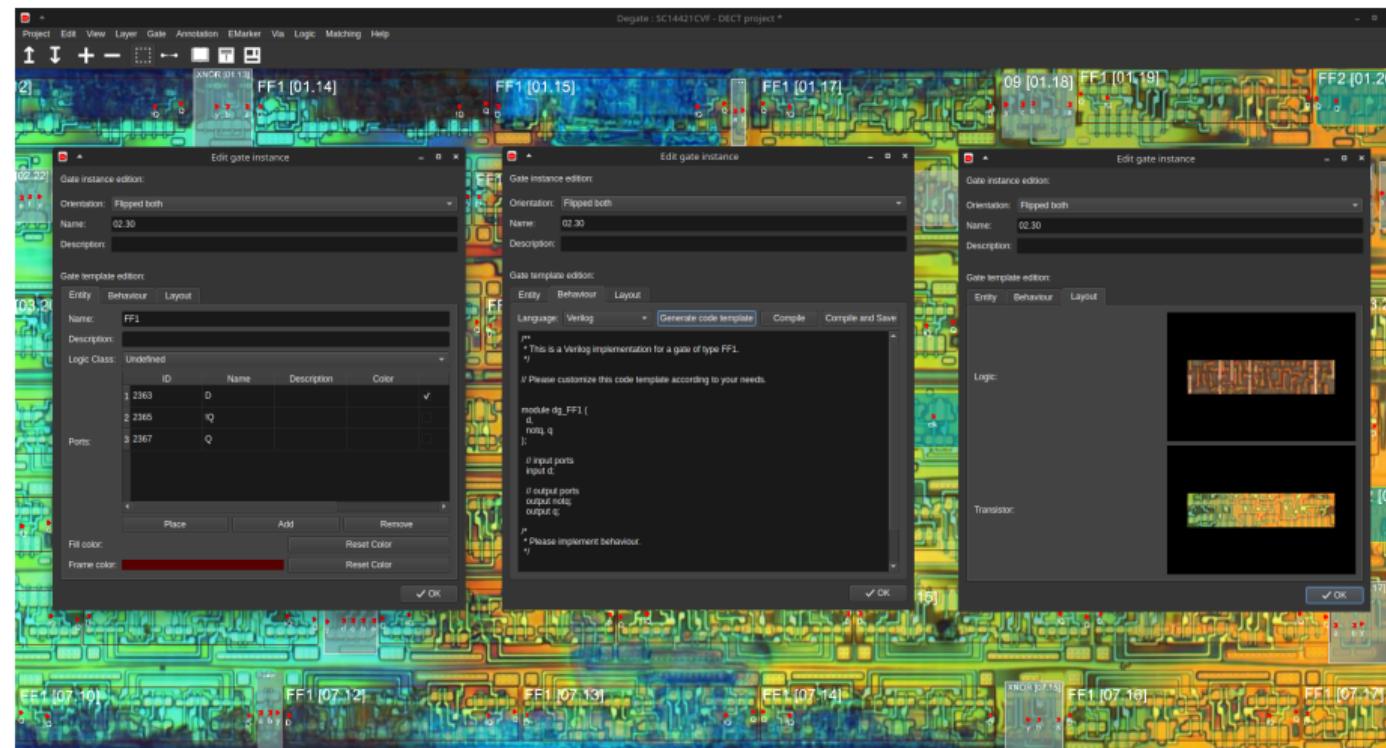
Small Demonstration



Each gate can be described with VHDL/Verilog, have a list of port (placed on image), a type associated etc.



Small Demonstration



Each identified gate (from the gate library) can be matched manually or using template matching algorithms.



Small Demonstration

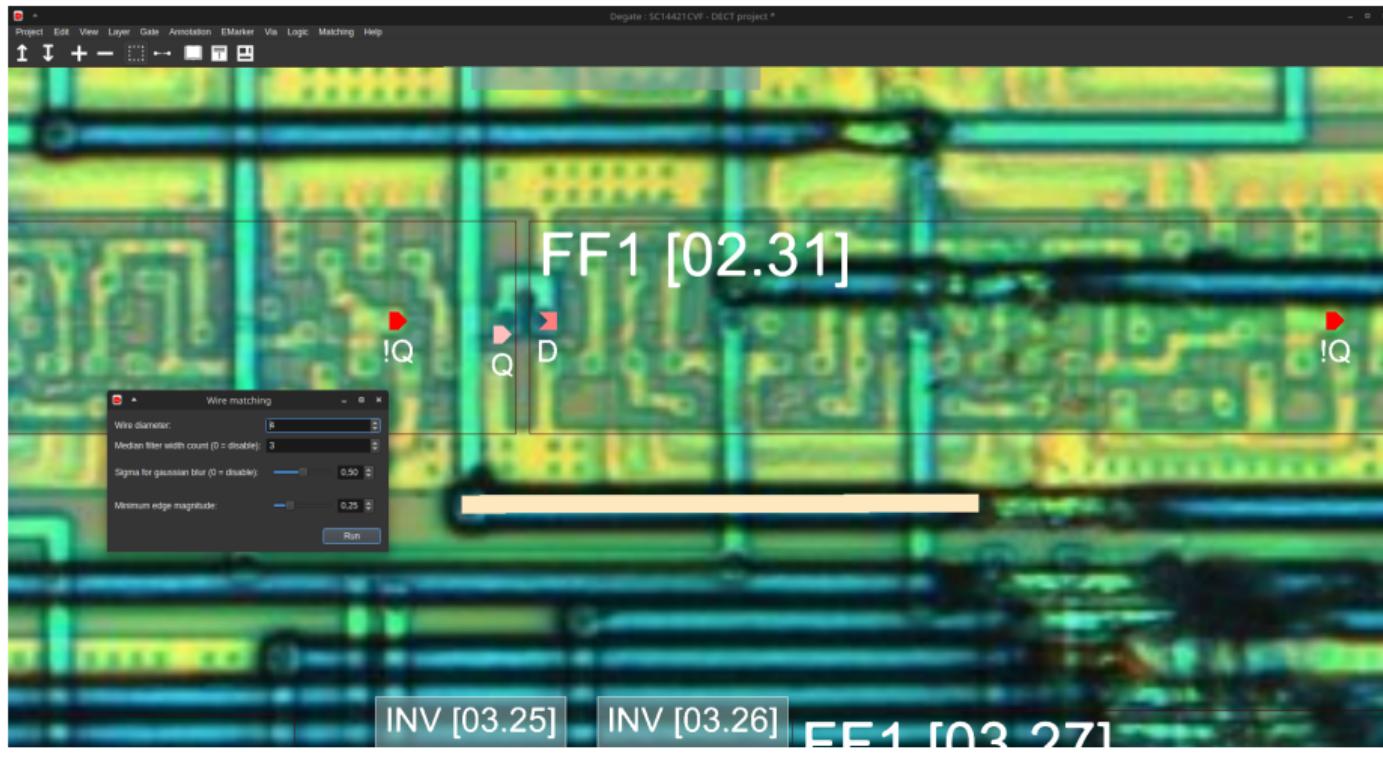


Template matching (will soon be ported to OpenCV) will use gate library to automate gate identification.

Currently it uses normalized cross-correlation (with some more steps).



Small Demonstration

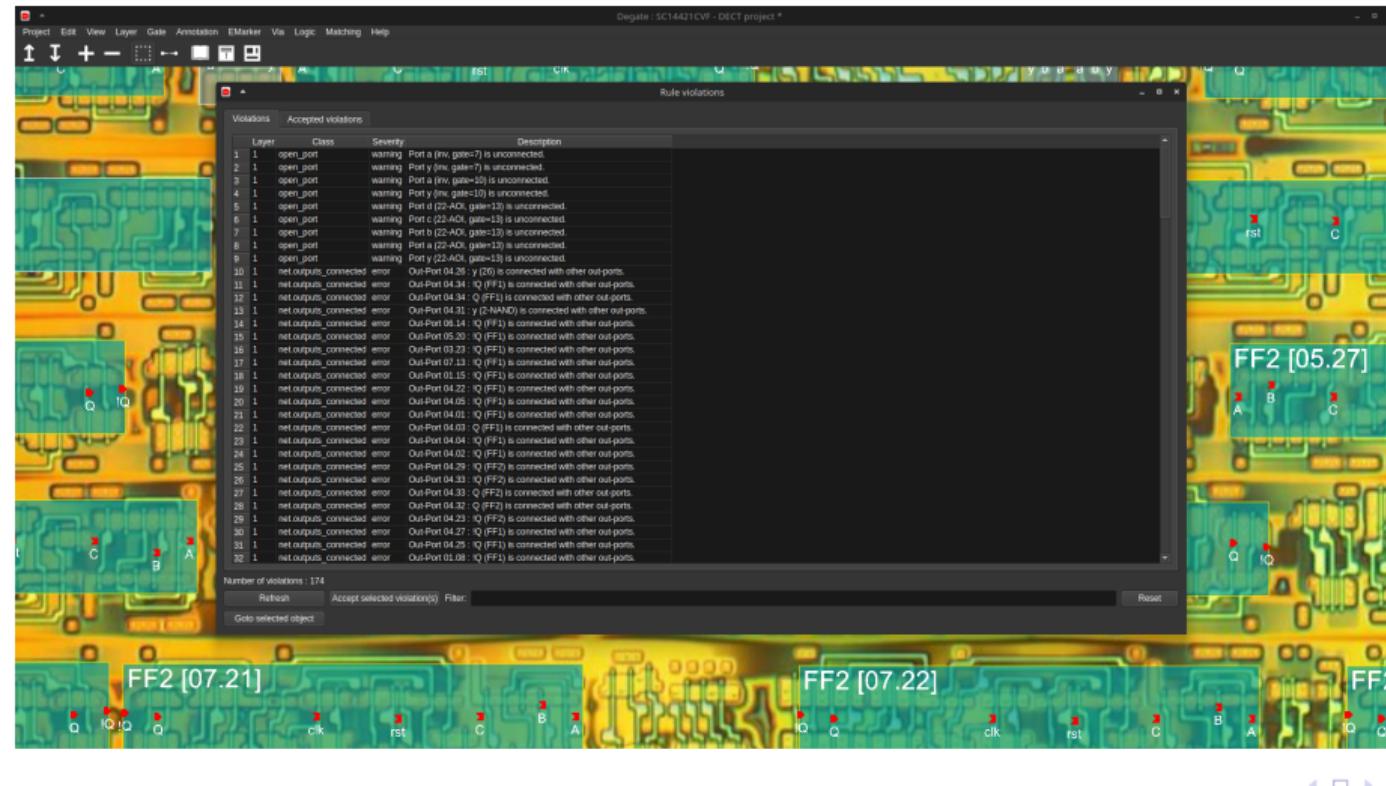


Wire matching, and specifically port interconnection, is the real challenge (and very error prone).

Currently it uses zero crossing edge detection.



Small Demonstration



Helpers are available, like rudimentary (but to be improved) rule checking (e.g. for coherency).

Small Demonstration



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References I

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- [2] Starbug Karsten Nohl.
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- [4] John McMaster.
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- [6] Martin Schobert.
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References III

[8] Ken Shirriff.

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[9] Mikhail Svarichevsky.

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[10] Zonenberg Andrew Yener Bulent.

Csci 4974/6974 hardware reverse engineering, 2014.



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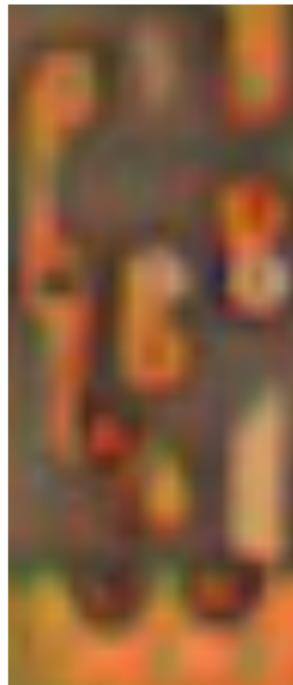
4 Bonus



Which gate is this?



Transistor layer



Logic layer



Metal layer

